	Se	arcn	notes	

Application/Control No.	Applicant(s)/Patent under Reexamination	_
10/774,775	KIM ET AL.	
Examiner	Art Unit	
Daniel B. Ko	2189	

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Class	Subclass	Date	Examiner
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INT	INTERFERENCE SEARCHED		
Class	Subclass	Date	Examiner
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SEARCH NOT (INCLUDING SEARCH		)
	DATE	EXMR
PLUS Search	3/23/2006	DBK
EAST text search (see EAST search history print out)	3/27/2006	DBK
711/119 (text search only - see search history printout)	3/25/2006	DBK
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